

MOSFETs Silicon P-/N-Channel MOS

SSM6L56FE

1. Applications

· High-Speed Switching

2. Features

- (1) 1.5-V drive
- (2) Low drain-source on-resistance

Q1 N-channel:

$$\begin{split} R_{DS(ON)} &= 235~\text{m}\Omega~(\text{max})~(\text{@V}_{GS} = 4.5~\text{V},~I_D = 800~\text{mA}) \\ R_{DS(ON)} &= 300~\text{m}\Omega~(\text{max})~(\text{@V}_{GS} = 2.5~\text{V},~I_D = 600~\text{mA}) \end{split}$$

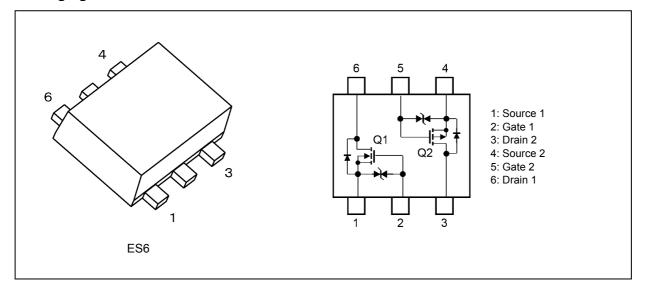
 $R_{DS(ON)}$ = 480 mW (max) (@V_{GS} = 1.8 V, I_D = 200 mA)

 $R_{DS(ON)}$ = 840 m Ω (max) (@ V_{GS} = 1.5 V, I_{D} = 50 mA)

Q2 P-channel:

$$\begin{split} R_{DS(ON)} &= 390 \text{ m}\Omega \text{ (max) (@V_{GS} = -4.5 \text{ V}, I_D = -800 \text{ mA)}} \\ R_{DS(ON)} &= 480 \text{ m}\Omega \text{ (max) (@V_{GS} = -2.5 \text{ V}, I_D = -500 \text{ mA)}} \\ R_{DS(ON)} &= 660 \text{ m}\Omega \text{ (max) (@V_{GS} = -1.8 \text{ V}, I_D = -200 \text{ mA)}} \\ R_{DS(ON)} &= 900 \text{ m}\Omega \text{ (max) (@V_{GS} = -1.5 \text{ V}, I_D = -100 \text{ mA)}} \\ R_{DS(ON)} &= 4000 \text{ m}\Omega \text{ (max) (@V_{GS} = -1.2 \text{ V}, I_D = -10 \text{ mA)}} \end{split}$$

3. Packaging and Internal Circuit



Start of commercial production



4. Absolute Maximum Ratings (Note)

4.1. Q1 Absolute Maximum Ratings (Unless otherwise specified, T_a = 25 °C)

Characteristics		Symbol	Rating	Unit
Drain-source voltage		V_{DSS}	20	V
Gate-source voltage		V_{GSS}	±8	
Drain current (DC)	(Note 1)	I _D	800	mA
Drain current (pulsed)	(Note 1)	I _{DP}	1600	

Note 1: Ensure that the channel temperature does not exceed 150 °C.

4.2. Q2 Absolute Maximum Ratings (Unless otherwise specified, T_a = 25 °C)

Characteristics		Symbol	Rating	Unit
Drain-source voltage		V _{DSS}	-20	V
Gate-source voltage		V _{GSS}	±8	
Drain current (DC)	(Note 1)	I _D	-800	mA
Drain current (pulsed)	(Note 1)	I _{DP}	-1600	

Note 1: Ensure that the channel temperature does not exceed 150 °C.

4.3. Absolute Maximum Ratings (Unless otherwise specified, T_a = 25 °C) (Q1, Q2 Common)

Characteristics		Symbol	Rating	Unit
Power dissipation	(Note 1)	P_D	150	mW
Power dissipation	(Note 2)		250	
Channel temperature		T _{ch}	150	°C
Storage temperature	-	T _{stg}	-55 to 150	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: Device mounted on an FR4 board.(total rating) (25.4 mm \times 25.4 mm \times 1.6 mm, Cu pad: 0.135 mm² \times 6)

Note 2: Device mounted on an FR4 board.(total rating) (25.4 mm × 25.4 mm × 1.6 mm, Cu pad: 645 mm²)

Note: The MOSFETs in this device are sensitive to electrostatic discharge. When handling this device, the worktables, operators, soldering irons and other objects should be protected against anti-static discharge.

Note: The channel-to-ambient thermal resistance, R_{th(ch-a)}, and the drain power dissipation, P_D, vary according to the board material, board area, board thickness and pad area. When using this device, be sure to take heat dissipation fully into account.

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5. Electrical Characteristics

5.1. Q1 Static Characteristics (Unless otherwise specified, Ta = 25 °C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 6 \text{ V}$	_	_	±1	μА
Drain cut-off current		I _{DSS}	V _{DS} = 16 V, V _{GS} = 0 V	_	_	1	
Drain-source breakdown voltage		V _{(BR)DSS}	I _D = 1 mA, V _{GS} = 0 V	20	_	_	V
Drain-source breakdown voltage	(Note 1)	V _{(BR)DSX}	I _D = 1 mA, V _{GS} = -5 V	15	_	_	
Gate threshold voltage	(Note 2)	V_{th}	V _{DS} = 3 V, I _D = 1 mA	0.4	_	1.0	
Drain-source on-resistance	(Note 3)	R _{DS(ON)}	I _D = 800 mA, V _{GS} = 4.5 V	_	186	235	mΩ
			I _D = 600 mA, V _{GS} = 2.5 V	_	230	300	
			I _D = 200 mA, V _{GS} = 1.8 V	_	290	480	
			I _D = 50 mA, V _{GS} = 1.5 V	_	360	840	
Forward transfer admittance	(Note 3)	Y _{fs}	V _{DS} = 3 V, I _D = 200 mA	_	1.4		S

Note 1: If a reverse bias is applied between gate and source, this device enters $V_{(BR)DSX}$ mode. Note that the drain-source breakdown voltage is lowered in this mode.

Note 2: Let V_{th} be the voltage applied between gate and source that causes the drain current (I_D) to below (1 mA for this device). Then, for normal switching operation, $V_{GS(ON)}$ must be higher than V_{th} , and $V_{GS(OFF)}$ must be lower than V_{th} . This relationship can be expressed as: $V_{GS(OFF)} < V_{th} < V_{GS(ON)}$.

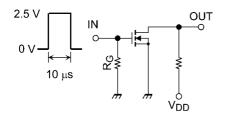
Take this into consideration when using the device.

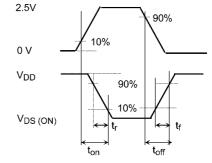
Note 3: Pulse measurement.

5.2. Q1 Dynamic Characteristics (Unless otherwise specified, T_a = 25 °C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Input capacitance	C _{iss}	V _{DS} = 10 V , V _{GS} = 0 V,	_	55		pF
Reverse transfer capacitance	C _{rss}	f = 1 MHz	_	6		
Output capacitance	C _{oss}		_	16		
Switching time (turn-on time)	t _{on}	V _{DD} = 10 V, I _D = 200 mA,	_	5.5	_	ns
Switching time (turn-off time)	t _{off}	V_{GS} = 0 to 2.5 V, R_{G} = 50 Ω	_	8.5		

5.3. Q1 Switching Time Test Circuit





Switching Time Test Circuit

Input Waveform/Output Waveform

5.4. Q1 Gate Charge Characteristics (Unless otherwise specified, T_a = 25 °C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Total gate charge (gate-source plus gate-drain)	Q_g	V_{DD} = 10 V, I_{D} = 800 mA,	_	1.0	_	nC
Gate-source charge 1	Q _{gs1}	V _{GS} = 4.5 V	_	0.12	_	
Gate-drain charge	Q _{gd}		_	0.4	_	



5.5. Q1 Source-Drain Characteristics (Unless otherwise specified, Ta = 25 °C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Diode forward voltage	(Note 1)	V_{DSF}	I_D = -800 mA, V_{GS} = 0 V	_	-0.82	-1.2	V

Note 1: Pulse measurement.

5.6. Q2 Static Characteristics (Unless otherwise specified, T_a = 25 °C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 8 \text{ V}$	_	_	±1	μА
Drain cut-off current		I _{DSS}	V _{DS} = -20 V, V _{GS} = 0 V	_	_	-1	
Drain-source breakdown voltage		V _{(BR)DSS}	I _D = -1 mA, V _{GS} = 0 V	-20	_	_	V
Drain-source breakdown voltage	(Note 1)	$V_{(BR)DSX}$	I _D = -1 mA, V _{GS} = 5 V	-15	_	_	
Gate threshold voltage	(Note 2)	V_{th}	$V_{DS} = -3 \text{ V}, I_{D} = -1 \text{ mA}$	-0.3	_	-1.0	
Drain-source on-resistance	(Note 3)	R _{DS(ON)}	I_D = -800 mA, V_{GS} = -4.5 V	_	310	390	mΩ
			I _D = -500 mA, V _{GS} = -2.5 V	_	380	480	
			I _D = -200 mA, V _{GS} = -1.8 V	_	470	660	
			I _D = -100 mA, V _{GS} = -1.5 V	_	560	900	
			I _D = -10 mA, V _{GS} = -1.2 V	_	770	4000	
Forward transfer admittance	(Note 3)	Y _{fs}	$V_{DS} = -3 \text{ V}, I_{D} = -100 \text{ mA}$	0.5	1.0		S

Note 1: If a reverse bias is applied between gate and source, this device enters V_{(BR)DSX} mode. Note that the drain-source breakdown voltage is lowered in this mode.

Note 2: Let V_{th} be the voltage applied between gate and source that causes the drain current (I_D) to below (-1 mA for this device). Then, for normal switching operation, $V_{GS(ON)}$ must be higher than V_{th} , and $V_{GS(OFF)}$ must be lower than V_{th} . This relationship can be expressed as: $V_{GS(OFF)} < V_{th} < V_{GS(ON)}$.

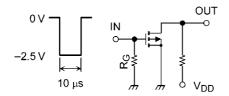
Take this into consideration when using the device.

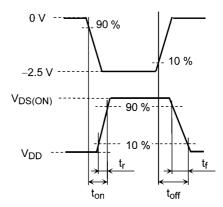
Note 3: Pulse measurement.

5.7. Q2 Dynamic Characteristics (Unless otherwise specified, T_a = 25 °C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Input capacitance	C _{iss}	V _{DS} = -10 V , V _{GS} = 0 V,	_	100	_	pF
Reverse transfer capacitance	C _{rss}	f = 1 MHz	_	10	_	
Output capacitance	C _{oss}		_	16	_	
Switching time (turn-on time)	t _{on}	V _{DD} = -10 V, I _D = -200 mA,	_	8	_	ns
Switching time (turn-off time)	t _{off}	V_{GS} = 0 to -2.5 V, R_{G} = 50 Ω	_	26	_	

5.8. Q2 Switching Time Test Circuit





Switching Time Test Circuit

Input Waveform/Output Waveform

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5.9. Q2 Gate Charge Characteristics (Unless otherwise specified, T_a = 25 °C)

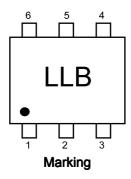
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Total gate charge (gate-source plus gate-drain)	9	$V_{DD} = -10 \text{ V}, I_D = -800 \text{ mA},$	_	1.6	_	nC
Gate-source charge 1	Q _{gs1}	V _{GS} = -4.5 V	_	0.2	_	
Gate-drain charge	Q _{gd}		_	0.4	_	

5.10. Q2 Source-Drain Characteristics (Unless otherwise specified, T_a = 25 °C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Diode forward voltage (N	ote 1)	V_{DSF}	$I_D = 800 \text{ mA}, V_{GS} = 0 \text{ V}$	_	0.9	1.2	V

Note 1: Pulse measurement.

6. Marking





7. Characteristics Curves (Note)

7.1. Q1 Characteristics Curves

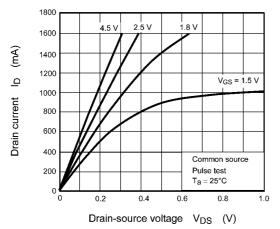


Fig. 7.1.1 I_D - V_{DS}

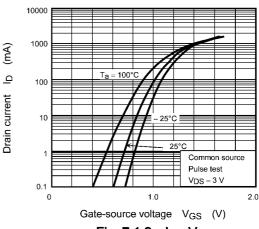


Fig. 7.1.2 I_D - V_{GS}

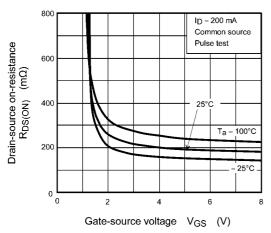


Fig. 7.1.3 R_{DS(ON)} - V_{GS}

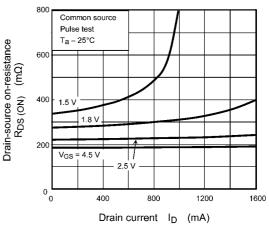


Fig. 7.1.4 R_{DS(ON)} - I_D

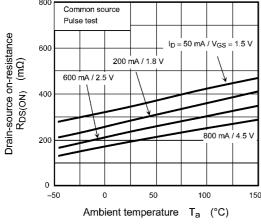


Fig. 7.1.5 R_{DS(ON)} - T_a

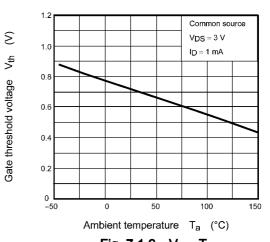


Fig. 7.1.6 V_{th} - T_a

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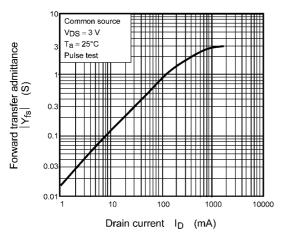


Fig. 7.1.7 |Yfs| - ID

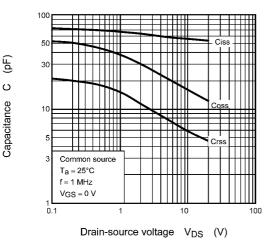


Fig. 7.1.9 C - V_{DS}

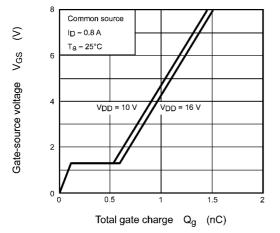


Fig. 7.1.11 Dynamic Input Characteristics

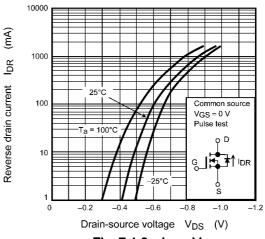


Fig. 7.1.8 I_{DR} - V_{DS}

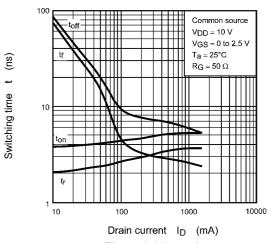


Fig. 7.1.10 t - I_D



7.2. Q2 Characteristics Curves

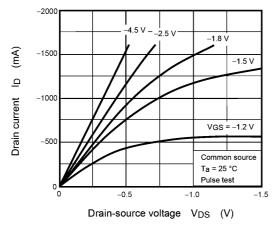


Fig. 7.2.1 I_D - V_{DS}

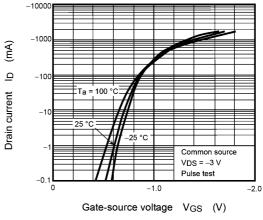


Fig. 7.2.2 I_D - V_{GS}

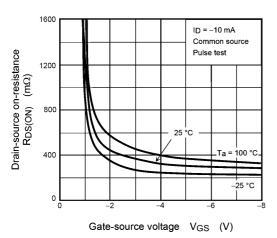


Fig. 7.2.3 R_{DS(ON)} - V_{GS}

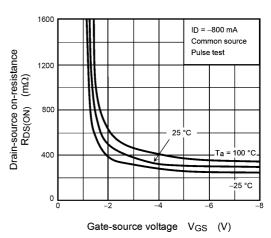


Fig. 7.2.4 R_{DS(ON)} - V_{GS}

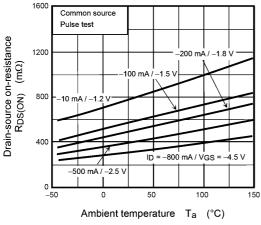


Fig. 7.2.5 $R_{DS(ON)}$ - T_a

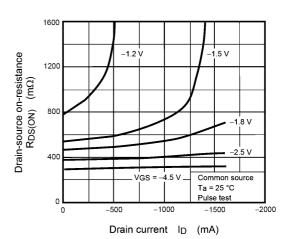


Fig. 7.2.6 R_{DS(ON)} - I_D

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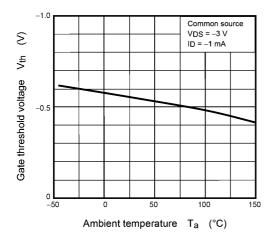


Fig. 7.2.7 V_{th} - T_a

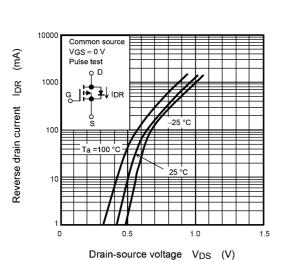
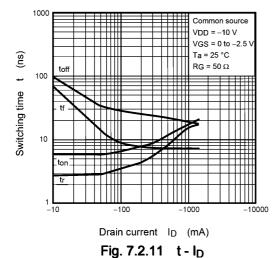


Fig. 7.2.9 I_{DR} - V_{DS}



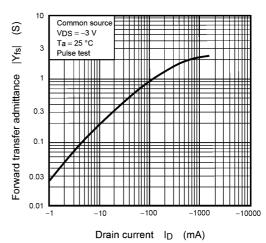


Fig. 7.2.8 |Y_{fs}| - I_D

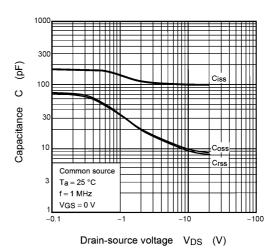


Fig. 7.2.10 C - V_{DS}

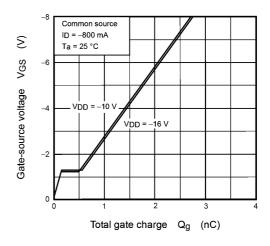
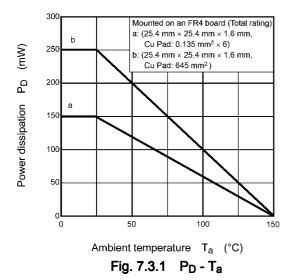


Fig. 7.2.12 Dynamic Input Characteristics



7.3. Characteristics Curves (Q1, Q2 Common)

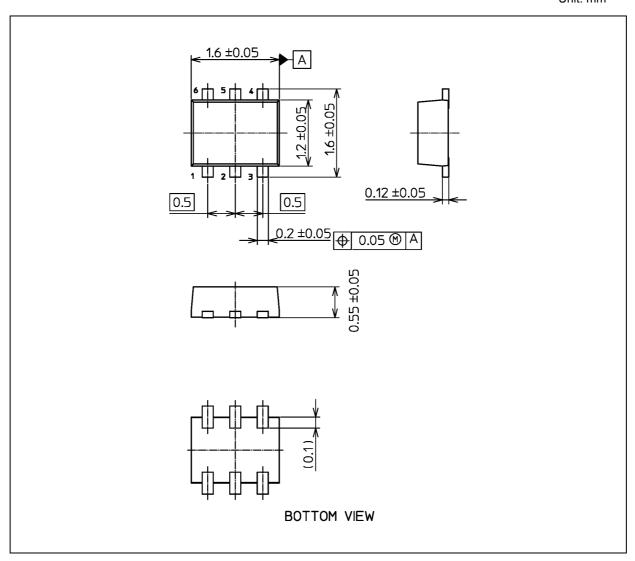


Note: The above characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.



Package Dimensions

Unit: mm



Weight: 3.0 mg (typ.)

	Package Name(s)	
Nickname: ES6		

Rev.1.0



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